

**Search Notes**

Application/Control No.

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Examiner

Christopher L. Chin

Applicant(s)/Patent under  
Reexamination

NAYA ET AL.

Art Unit

1641

**SEARCHED**

Class	Subclass	Date	Examiner
Updated	search	7/10/2006	CC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR